Citations for Ion : W

Pub. Year	Authors, Title, Journal Citation and Comments	Citation Numb
1963	Uhler, J. Domeij, B. Borg, S. **'Range Distributions of W187 Ions of keV Energies in Tungsten'** ***Arkiv. Fysik, 24, 413-19 (1963)*** *Comment : R, dR. 1.6-127 keV 187W -> W*	**1963-Uhle**
1967	Erikson, L. Davies, J. A. Jespersgaard, P. **'Range Measurements in Oriented Tungsten Single Crystals (0.1-1.0 MeV). Part I: Electronic and Nuclear Stopping Powers.'** ***Phys. Rev., 161, 219-34 (1967)*** *Comment : R, dR. (0.1-1.0 MeV) Na, P, K, Cr, Cu, Br, Kr, Rb, Sb, Xe, W, Rn -> W (Cryst.); (40-500 keV) Na, K, Kr, Xe -> Al (Cryst.)*	**1967-Erik2**
1967	Lehmann, L. Spehl, H. Wertz, N. **'A New Method for Range Measurements of Very Heavy Ions using Coulomb Excitation and Perturbed Angular Correlations'** ***Nucl. Inst. Methods, 55, 201-04 (1967)*** *Comment : R. 0.8 MeV W -> Cu*	**1967-Lehm**
1968	Hvelplund, P. Fastrup, B. **'Stopping Cross Section in Carbon of 0.2 - 1.5 MeV Atoms with 21 <= Z1 <= 39.'** ***Phys. Rev., 165, 408-14 (1968)*** *Comment : S. (230 - 1470 keV) Sc, Ti, Cr, Mn, Fe, Co, Cu, Ge, Br, W, Y -> C*	**1968-Hvel2**
1974	Grant, W. A. Williams, J. S. Dodds, D. **'Measurement of Projected and Lateral Range Parameters for Low Energy Heavy Ions in Silicon by Rutherford Backscattering'** ***Meyer, G. Linker and F. Kappeler (Ed.):Ion Beam Surface Layer Analysis, Plenum, N. Y., P. 235-44 (1974)*** *Comment : R, dR, dR(Lateral). 10-80 keV Pb, 50-400 keV Bi, 40 keV Ar, Cu, Kr, Cd, Al, Dy, W -> Si*	**1974-Gran**
1976	Grant, W. A. Williams, J. S. Dodds, D. **'Measurement of the Lateral Spread of Heavy Ions Implanted into Silicon'** ***Rad. Effects, 29, 189-90 (1976)*** *Comment : dR(Lateral). (10-40 keV) Cu, Cd, Xe, Dy, Kr, W, Pb, Bi -> Si*	**1976-Gran3**
1983	Geissel, H. Laichter, Y. Schneider, W. F. W. Armbruster, P. **'On the Effective Charges from Stopping Powers of 0.5-10 MeV/amu Heavy Ions'** ***Phys. Letters, 99A, no. 2-3, 77-80 (1983)*** *Comment : S. Kr, Xe, W, Pb, U (1-6 MeV/amu) -> 13 metallic foils*	**1983-Geis**